Y. DOCKET NO. Form PTO-1449 JUL 2 1 2004 APPLICATION NO. 10/796,990 Ø35-0165P INFORMATION DISCLOSURE CITATION PPLICANT MIURA, Yasuyuki et al. ETRADEMAN! IN AN APPLICATION (Use several sheets if necessary) FILING DATE GROUP UNASSIGNED 2609 March 11, 2004 U.S. PATENT DOCUMENTS FILING DATE DOCUMENT NUMBER Kind DATE US US IIS FOREIGN PATENT DOCUMENTS CLASS TRANSLATION Office DOCUMENT Kind DATE COUNTRY NUMBER OTHER DOCUMENTS (Include Name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.) date, page(s), volume-issue number(s), publisher, city and/or country where published. DALLY et al., "Deadlock-Free Adaptive Routing in Multicomputer Networks Using Virtual Channels," IEEE Transactions on Parallel and Distributed Systems, Vol. 4, No. 4, /WK/ April 1993, pp. 466-475. DUATO, "A New Theory of Deadlock-Free Adaptive Routing in Wormhole Networks," IEE /WK/ Transactions on Parallel and Distributed Systems, Vol. 4, No. 12, December 1993, pp. 1320-1331. YANG et al., "Adaptive Routing in k-ary n-cube Multicomputers," Proc. Of ICPADS, /WK/ 1996, pp. 404-411 JAIN et al., "TESH: A New Hierarchical Interconnection Network for Massively Parallel Computing," IEICE Trans. Inf. & Syst., Vol. E80-D, No. 9, September 1997, pp. 837-/WK/ 845. HORIGUCHI, "Wafer Scale Integration," Proceedings of the 6th International /WK/ Microelectronics Conference," May 30-June 1, 1990, Tokyo Japan, pp. 51-58. LITTLE et al., "The 3-D Computer," IEEE International Conference on Wafer Scale /WK/ Integration, 1989, pp. 55-64. CAMPBELL et al., "3-D Wafer Stack Neurocomputing," IEEE International Conference on /WK/ Wafer Scale Integration, 1993, pp. 67-74. CARSON, "The Emergence of Stacked 3D Silicon and its Impact on Microelectronics /WK/ Systems Integration," IEEE Innovative Systems in Silicon, 1996, pp. 1-8. KURINO et al., "Three-Dimensional Integration Technology for Real Time Micro-Vision System," IEEE International Conference on Innovative Systems in Silicon, 1997, pp. /WK/ 203-212. EXAMINER DATE CONSIDERED /Wei Po Kao/ (09/02/2007)

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